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			APPLICANT Takeshi ONO, et al.			
			FILING DATE March 05, 2002	GROUP 2641		
<b>U.S. PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codes ( <i>i</i> f known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document		
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<b>FOREIGN PATENT DOCUMENTS</b>						
EXAMINER'S INITIALS	CITE NO.	Foreign Patent Document Country Codes-Number + Kind Codes ( <i>i</i> f known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Figures Appear	Translation Yes      No
DLS		JP 11-052984	02/26/1999	FUJITSU LTD		abstract
DLS		JP 2002-041078	02/08/2002	SHARP CORP		abstract
<b>OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)</b>						
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